

# **RMLV0816BGSB - 4S2**

8Mb Advanced LPSRAM (512k word × 16bit)

R10DS0231EJ0200 Rev.2.00 2015.06.26

### **Description**

The RMLV0816BGSB is a family of 8-Mbit static RAMs organized 524,288-word  $\times$  16-bit, fabricated by Renesas's high-performance Advanced LPSRAM technologies. The RMLV0816BGSB has realized higher density, higher performance and low power consumption. The RMLV0816BGSB offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It is offered in 44pin TSOP (II).

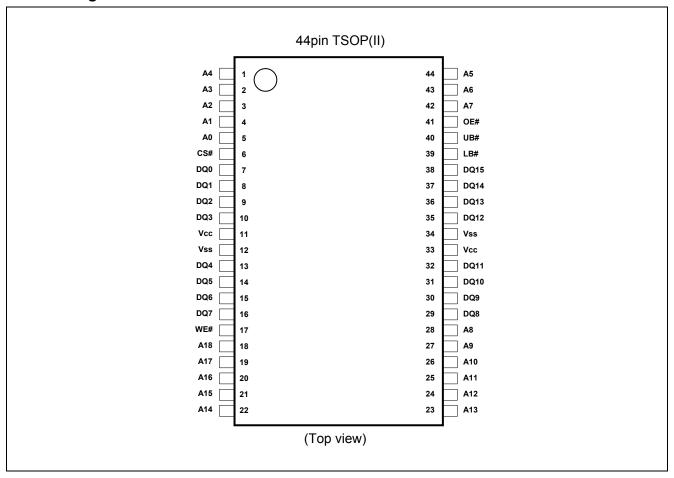
#### **Features**

- Single 3V supply: 2.4V to 3.6V
- Access time:
  - Power supply voltage from 2.7V to 3.6V: 45ns (max.)
  - Power supply voltage from 2.4V to 2.7V: 55ns (max.)
- Current consumption:
  - Standby: 0.45μA (typ.)
- Equal access and cycle times
- Common data input and output
  - Three state output
- Directly TTL compatible
  - All inputs and outputs
- Battery backup operation

#### **Part Name Information**

Part Name	Power supply	Access time	Temperature Range	Package
RMLV0816BGSB-4S2	2.7V to 3.6V	45 ns	40 - +95°C	11.76mm×18.41mm 44pin plastic TSOP(II)
RIVIL V 00 10 B G 3 B - 4 3 2	2.4V to 2.7V	55 ns	-40 ~ +85°C	11.70mm^10.4 mm 44pm plastic 150P(ii)

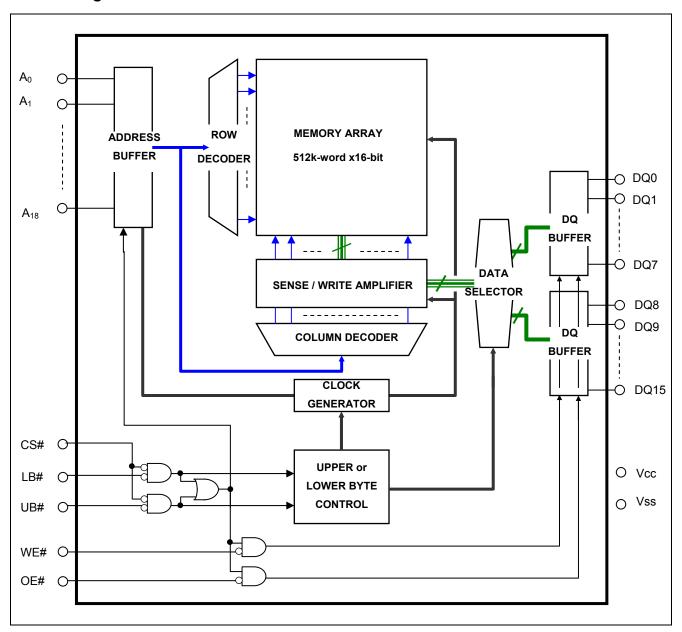
# **Pin Arrangement**



# **Pin Description**

Pin name	Function
V <sub>CC</sub>	Power supply
V <sub>SS</sub>	Ground
A0 to A18	Address input
DQ0 to DQ15	Data input/output
CS#	Chip select
OE#	Output enable
WE#	Write enable
LB#	Lower byte select
UB#	Upper byte select

# **Block Diagram**



# **Operation Table**

CS#	WE#	OE#	UB#	LB#	DQ0 to DQ7	DQ8 to DQ15	Operation
Н	X	Χ	Χ	Χ	High-Z	High-Z	Standby
Х	Х	Х	Н	Н	High-Z	High-Z	Standby
L	Н	L	L	L	Dout	Dout	Read
L	Н	L	Н	L	Dout	High-Z	Lower byte read
L	Н	L	L	Н	High-Z	Dout	Upper byte read
L	L	Х	L	L	Din	Din	Write
L	L	Х	Н	L	Din	High-Z	Lower byte write
L	L	Х	L	Н	High-Z	Din	Upper byte write
L	Н	Н	Х	Х	High-Z	High-Z	Output disable

Note 1. H:  $V_{IH}$  L: $V_{IL}$  X:  $V_{IH}$  or  $V_{IL}$ 

### **Absolute Maximum Ratings**

Parameter	Symbol	Value	unit
Power supply voltage relative to V <sub>SS</sub>	V <sub>CC</sub>	-0.5 to +4.6	V
Terminal voltage on any pin relative to V <sub>SS</sub>	V <sub>T</sub>	-0.5 <sup>*2</sup> to V <sub>CC</sub> +0.3 <sup>*3</sup>	V
Power dissipation	P <sub>T</sub>	0.7	W
Operation temperature	Topr	-40 to +85	°C
Storage temperature range	Tstg	-65 to +150	°C
Storage temperature range under bias	Tbias	-40 to +85	°C

Note 2. -3.0V for pulse ≤ 30ns (full width at half maximum)

# **DC Operating Conditions**

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions	Note
Supply voltage	Vcc	2.4	3.0	3.6	<b>V</b>		
	Vss	0	0	0	<b>V</b>		
land think waltana		2.0	-	V <sub>CC</sub> +0.2	<b>V</b>	Vcc=2.4V to 2.7V	
Input high voltage	$V_{IH}$	2.2	_	V <sub>CC</sub> +0.2	V	Vcc=2.7V to 3.6V	
lanut lauruslitana	\/	-0.2	_	0.4	V	Vcc=2.4V to 2.7V	4
Input low voltage	$V_{IL}$	-0.2	_	0.6	V	Vcc=2.7V to 3.6V	4
Ambient temperature range	Та	-40	_	+85	°C		

Note 4. -3.0V for pulse  $\leq$  30ns (full width at half maximum)

#### **DC Characteristics**

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions			
Input leakage current		I	_	1	μА	Vin = V <sub>SS</sub> to V <sub>CC</sub>			
Output leakage current	I <sub>LO</sub>	ı	_	1	μΑ		H or OE# = $V_{IH}$ or WE# = $V_{IL}$ UB# = $V_{IH}$ , $V_{I/O}$ = $V_{SS}$ to $V_{CC}$		
Average operating current		ı	20 <sup>*5</sup>	25	mA	_	55ns, duty =100%, I <sub>I/O</sub> = 0mA, <sub>L</sub> , Others = V <sub>IH</sub> /V <sub>IL</sub>		
	I <sub>CC1</sub>	_	25 <sup>*5</sup>	30	mA	_	5ns, duty =100%, I <sub>I/O</sub> = 0mA, <sub>L</sub> , Others = V <sub>IH</sub> /V <sub>IL</sub>		
	I <sub>CC2</sub>	ı	1.5 <sup>*5</sup>	3	mA	Cycle =1 $\mu$ s, duty =100%, $I_{I/O}$ = 0mA CS# $\leq$ 0.2V, $V_{IH} \geq V_{CC}$ -0.2V, $V_{IL} \leq$ 0.2V			
Standby current	$I_{SB}$	l	_	0.3	mA	CS# = V <sub>II</sub>	$_{H}$ , Others = $V_{SS}$ to $V_{CC}$		
Standby current		-	0.45 <sup>*5</sup>	2	μΑ	~+25°C			
		_	0.6*6	4	μА	~+40°C	Vin = $V_{SS}$ to $V_{CC}$ , (1) CS# $\geq$ $V_{CC}$ -0.2V or		
	I <sub>SB1</sub>	ı	_	7	μА	~+70°C	(2) LB# = UB# ≥ V <sub>CC</sub> -0.2V, CS# ≤ 0.2V		
		_	_	10	μΑ	~+85°C			
Output high voltage	V <sub>OH</sub>	2.4	_	_	>	I <sub>OH</sub> = -1mA Vcc≥2.7V			
	V <sub>OH2</sub>	2.0	_		V	I <sub>OH</sub> = -0.1mA			
Output low voltage	V <sub>OL</sub>	_	_	0.4	V	I <sub>OL</sub> = 2mA Vcc≥2.7V			
No. 5 Trial and the	V <sub>OL2</sub>	_	_	0.4	V	I <sub>OL</sub> = 0.1r	mA (T. 0500) and add 1000/ dead a		

Note 5. Typical parameter indicates the value for the center of distribution at 3.0V (Ta=25°C), and not 100% tested.

Note 6. Typical parameter indicates the value for the center of distribution at 3.0V (Ta=40°C), and not 100% tested.

<sup>3.</sup> Maximum voltage is +4.6V.

## Capacitance

 $(Ta = 25^{\circ}C, f = 1MHz)$ 

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions	Note
Input capacitance	C in	_	_	8	pF	Vin =0V	7
Input / output capacitance	C <sub>I/O</sub>	ı	1	10	pF	V <sub>I/O</sub> =0V	7

Note 7. This parameter is sampled and not 100% tested.

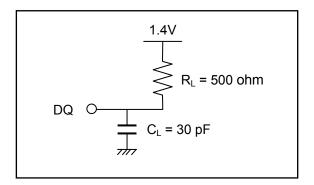
#### **AC Characteristics**

Test Conditions (Vcc =  $2.4V \sim 3.6V$ , Ta =  $-40 \sim +85$ °C)

• Input pulse levels:

$$V_{IL} = 0.4V$$
,  $V_{IH} = 2.4V$  (Vcc=2.7V to 3.6V)  
 $V_{IL} = 0.4V$ ,  $V_{IH} = 2.2V$  (Vcc=2.4V to 2.7V)

- Input rise and fall time: 5ns
- Input and output timing reference level: 1.4V
- Output load: See figures (Including scope and jig)



#### **Read Cycle**

Parameter	Cumbal	Vcc=2.7	V to 3.6V	Vcc=2.4	V to 2.7V	Unit	Note
Parameter	Symbol	Min.	Max.	Min.	Max.	Offic	Note
Read cycle time	t <sub>RC</sub>	45	-	55	_	ns	
Address access time	t <sub>AA</sub>	_	45	_	55	ns	
Chip select access time	t <sub>ACS</sub>	_	45	_	55	ns	
Output enable to output valid	t <sub>OE</sub>	_	22	_	30	ns	
Output hold from address change	t <sub>OH</sub>	10	_	10	_	ns	
LB#, UB# access time	t <sub>BA</sub>	_	45	_	55	ns	
Chip select to output in low-Z	t <sub>CLZ</sub>	10	_	10	_	ns	8,9
LB#, UB# enable to low-Z	t <sub>BLZ</sub>	5	_	5	_	ns	8,9
Output enable to output in low-Z	t <sub>OLZ</sub>	5	_	5	_	ns	8,9
Chip deselect to output in high-Z	t <sub>CHZ</sub>	0	18	0	20	ns	8,9,10
LB#, UB# disable to high-Z t <sub>BHZ</sub>		0	18	0	20	ns	8,9,10
Output disable to output in high-Z	t <sub>OHZ</sub>	0	18	0	20	ns	8,9,10

Note 8. This parameter is sampled and not 100% tested.

- 9. At any given temperature and voltage condition,  $t_{CHZ}$  max is less than  $t_{CLZ}$  min,  $t_{BHZ}$  max is less than  $t_{BLZ}$  min, and  $t_{OHZ}$  max is less than  $t_{OLZ}$  min, for any device.
- 10.  $t_{CHZ}$ ,  $t_{BHZ}$  and  $t_{OHZ}$  are defined as the time when the DQ pins enter a high-impedance state and are not referred to the DQ levels.

### **Write Cycle**

Parameter	Cumbal	Vcc=2.7	V to 3.6V	Vcc=2.4	V to 2.7V	Unit	Note
Parameter	Symbol	Min.	Max.	Min.	Max.	Unit	Note
Write cycle time	twc	45	_	55	_	ns	
Address valid to write end	t <sub>AW</sub>	35	_	50	_	ns	
Chip select to write end	t <sub>CW</sub>	35	_	50	_	ns	
Write pulse width	t <sub>WP</sub>	35	_	40	_	ns	11
LB#,UB# valid to write end	t <sub>BW</sub>	35	_	50	_	ns	
Address setup time to write start	t <sub>AS</sub>	0	_	0	_	ns	
Write recovery time from write end	t <sub>WR</sub>	0	_	0	_	ns	
Data to write time overlap	t <sub>DW</sub>	25	_	25	_	ns	
Data hold from write end		0	_	0	_	ns	
Output enable from write end tow		5	_	5	_	ns	12
Output disable to output in high-Z	e to output in high-Z t <sub>OHZ</sub>		18	0	20	ns	12,13
Write to output in high-Z		0	18	0	20	ns	12,13

Note 11.  $t_{WP}$  is the interval between write start and write end.

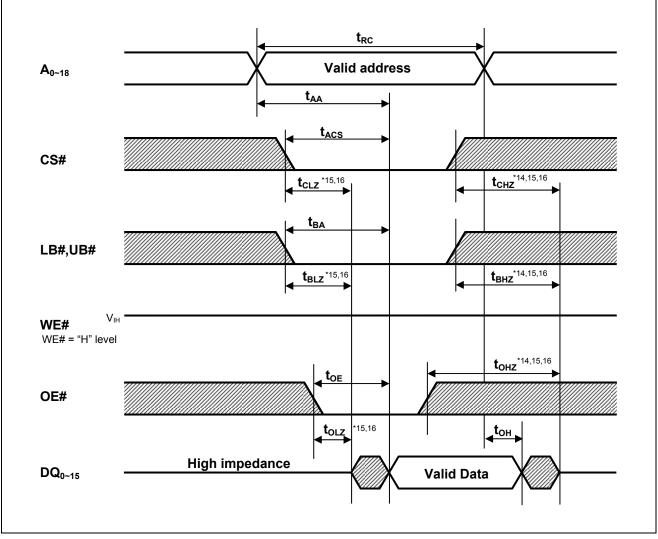
A write starts when all of (CS#), (WE#) and (one or both of LB# and UB#) become active.

A write is performed during the overlap of a low CS#, a low WE# and a low LB# or a low UB#.

- 12. This parameter is sampled and not 100% tested.
- 13.  $t_{OHZ}$  and  $t_{WHZ}$  are defined as the time when the DQ pins enter a high-impedance state and are not referred to the DQ levels.

### **Timing Waveforms**

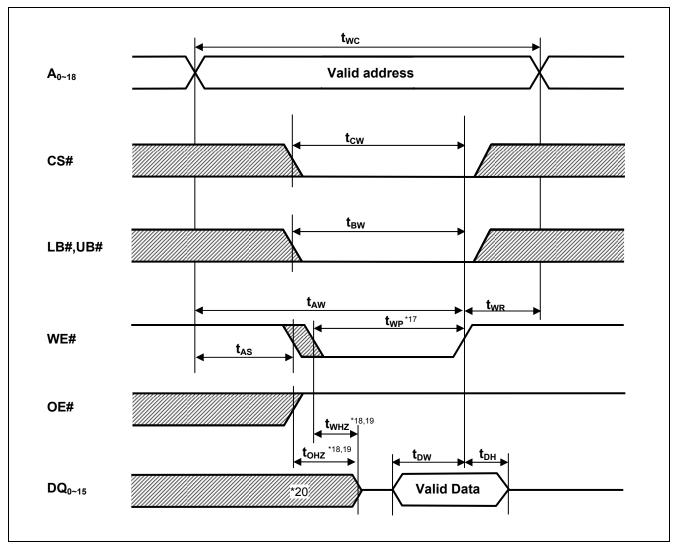
#### **Read Cycle**



Note 14.  $t_{CHZ}$ ,  $t_{BHZ}$  and  $t_{OHZ}$  are defined as the time when the DQ pins enter a high-impedance state and are not referred to the DQ levels.

- 15. This parameter is sampled and not 100% tested
- 16. At any given temperature and voltage condition,  $t_{CHZ}$  max is less than  $t_{CLZ}$  min,  $t_{BHZ}$  max is less than  $t_{BLZ}$  min, and  $t_{OHZ}$  max is less than  $t_{OLZ}$  min, for any device.

### Write Cycle (1) (WE# CLOCK, OE#="H" while writing)



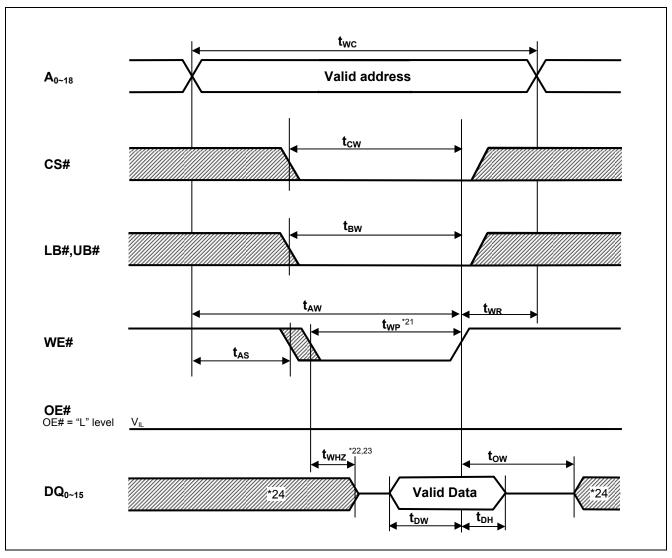
Note  $\,$  17.  $\,$   $t_{WP}$  is the interval between write start and write end.

A write starts when all of (CS#), (WE#) and (one or both of LB# and UB#) become active.

A write is performed during the overlap of a low CS#, a low WE# and a low LB# or a low UB#.

- 18.  $t_{OHZ}$  and  $t_{WHZ}$  are defined as the time when the DQ pins enter a high-impedance state and are not referred to the DQ levels.
- 19. This parameter is sampled and not 100% tested
- 20. During this period, DQ pins are in the output state so input signals must not be applied to the DQ pins.

#### Write Cycle (2) (WE# CLOCK, OE# Low Fixed)



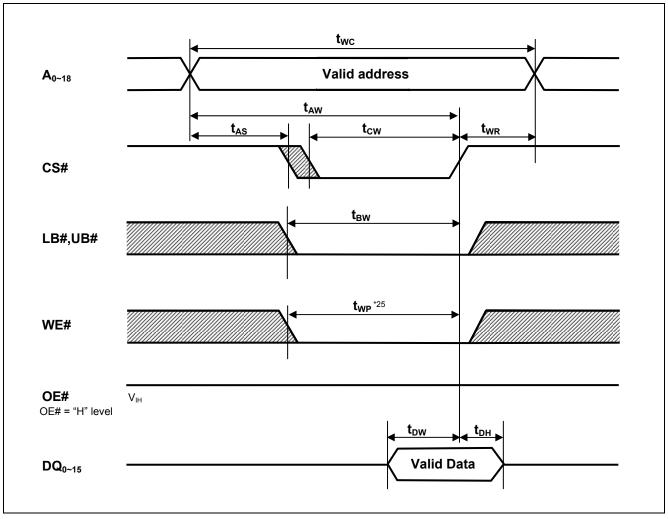
Note 21.  $t_{WP}$  is the interval between write start and write end.

A write starts when all of (CS#), (WE#) and (one or both of LB# and UB#) become active.

A write is performed during the overlap of a low CS#, a low WE# and a low LB# or a low UB#.

- 22.  $t_{WHZ}$  is defined as the time when the DQ pins enter a high-impedance state and are not referred to the DQ levels.
- 23. This parameter is sampled and not 100% tested.
- 24. During this period, DQ pins are in the output state so input signals must not be applied to the DQ pins.

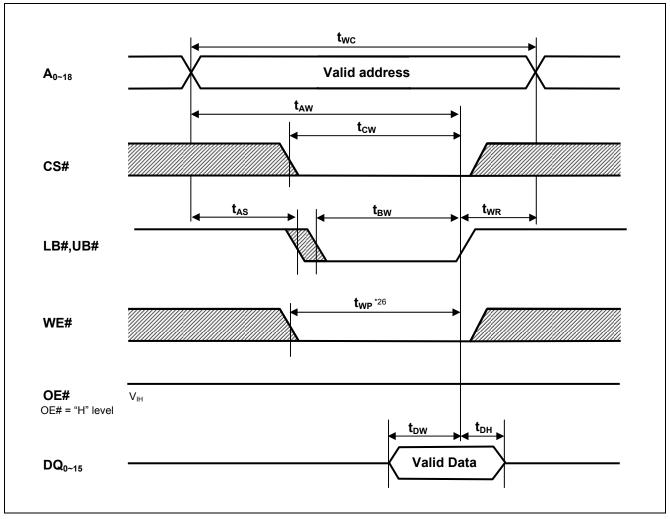
### Write Cycle (3) (CS# CLOCK)



Note 25. t<sub>WP</sub> is the interval between write start and write end.

A write starts when all of (CS#), (WE#) and (one or both of LB# and UB#) become active. A write is performed during the overlap of a low CS#, a low WE# and a low LB# or a low UB#.

### Write Cycle (4) (LB#, UB# CLOCK)



Note 26. t<sub>WP</sub> is the interval between write start and write end.

A write starts when all of (CS#), (WE#) and (one or both of LB# and UB#) become active.

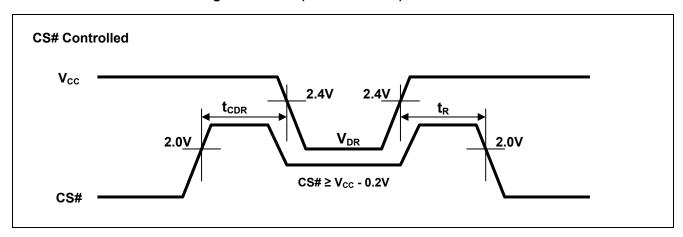
A write is performed during the overlap of a low CS#, a low WE# and a low LB# or a low UB#.

Low V<sub>CC</sub> Data Retention Characteristics

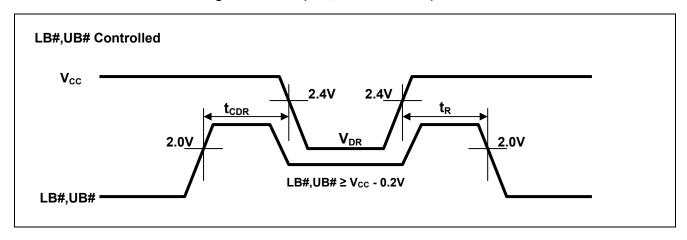
Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions*29		
V <sub>CC</sub> for data retention	$V_{DR}$	1.5	I	3.6	<b>V</b>	Vin ≥ 0V, (1) CS# ≥ $V_{CC}$ -0.2V or (2) LB# = UB# ≥ $V_{CC}$ -0.2V, CS# ≤ 0.2V		
Data retention current	ICCDR	_	0.45 <sup>*27</sup>	2	μΑ	~+25°C		
		_	0.6 <sup>*28</sup>	4	μΑ	~+40°C	$V_{CC}$ =3.0V, Vin ≥ 0V, (1) CS# ≥ $V_{CC}$ -0.2V or	
		_	-	7	μΑ	~+70°C	(2) LB# = UB# ≥ V <sub>CC</sub> -0.2V, CS# ≤ 0.2V	
		_	_	10	μΑ	~+85°C		
Chip deselect time to data retention	t <sub>CDR</sub>	0	_	_	ns	Con retention waveform		
Operation recovery time	t <sub>R</sub>	5		_	ms	See retention waveform.		

- Note 27. Typical parameter indicates the value for the center of distribution at 3.0V (Ta=25°C), and not 100% tested.
  - 28. Typical parameter indicates the value for the center of distribution at 3.0V (Ta=40°C), and not 100% tested.
  - 29. CS# controls address buffer, WE# buffer, OE# buffer, LB# buffer, UB# buffer and DQ buffer. If CS# controls data retention mode, Vin levels (address, WE#, OE#, LB#, UB#, DQ) can be in the high impedance state.

### Low Vcc Data Retention Timing Waveforms (CS# controlled)



#### Low Vcc Data Retention Timing Waveforms (LB#,UB# controlled)



Revision History

# RMLV0816BGSB Data Sheet

		Description						
Rev.	Date	Page	Summary					
1.00	2014.11.28	-	First Edition issued					
2.00	2015.06.26	P.1, 4	Standby current I <sub>SB1</sub> : 25°C 0.6μA ->0.45μA (typ.), 40°C 2μA ->0.6μA (typ.)					
		P.2	Modefy Pin Arrangement : Add 1pin Mark					
		P.4	Average operating current I <sub>CC2</sub> : 25°C 2mA ->1.5mA (typ.)					
		P.12	Data retention current I <sub>CCDR</sub> : 25°C 0.6μA ->0.45μA (typ.), 40°C 2μA ->0.6μA (typ.)					

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